

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Masayuki OIKAWA, et al.

GAU: 1773

SERIAL NO: 10/574,286

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EXAMINER: Cedric A. Chang

FOR: INSPECTION METHOD AND INSPECTION ASSISTING DEVICE FOR
QUARTZ PRODUCT OF SEMICONDUCTOR PROCESSING APPARATUS

SUBMISSION OF SUPPLEMENTAL APPLICATION DATA SHEET

Office of Initial Patent Examination
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicant(s) submit herewith a Supplemental Application Data Sheet for the above-identified application for the purpose of revising the title.

Respectfully Submitted,

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